

Notice of References Cited

Application/Control No.

10/618,597

Applicant(s)/Patent Under
Reexamination
EHRHART, MICHAEL

Examiner

Uyen-Chau N. Le

Art Unit

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Page 1 of 1

U.S. PATENT DOCUMENTS

| * | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|--|-----------------|------------------|----------------|
| A | US-6,438,638 B1 | 08-2002 | Jones et al. | 710/301 |
| B | US-6,524,137 B1 | 02-2003 | Liu et al. | 439/638 |
| C | US-6,718,274 B2 | 04-2004 | Huang et al. | 710/13 |
| D | US-6,725,291 B2 | 04-2004 | Lai et al. | 710/16 |
| E | US-6,744,634 B2 | 06-2004 | Yen, Sheng Shun | 439/377 |
| F | US-6,751,694 B2 | 06-2004 | Liu et al. | 710/301 |
| G | US-6,813,164 B2 | 11-2004 | Yen, Sheng Shun | 439/76.1 |
| H | US-6,813,668 B2 | 11-2004 | Tseng et al. | 710/301 |
| I | US-6,820,148 B1 | 11-2004 | Cedar et al. | 710/104 |
| J | US-6,832,281 B2 | 12-2004 | Jones et al. | 710/301 |
| K | US-6,839,864 B2 | 01-2005 | Mambakkam et al. | 714/5 |
| L | US-6,859,856 B2 | 02-2005 | Piau et al. | 710/10 |
| M | US-6,708,230 B2 | 03-2004 | Shin, Hyun-Bae | 710/9 |

FOREIGN PATENT DOCUMENTS

| * | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|--|-----------------|---------|------|----------------|
| N | | | | | |
| O | | | | | |
| P | | | | | |
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| R | | | | | |
| S | | | | | |
| T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|--|---|
| U | | |
| V | | |
| W | | |
| X | | |

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